

# CS18LV40965

## **Revision History**

<u>Rev. No.</u>	History	
2.0	Initial issue	
2.1	Revise DC characteristics	
2.2	Revise DC characteristics	

#### Issue Date

Dec. 13, 2007 Feb. 18, 2008 Apr. 03, 2008



# CS18LV40965

## GENERAL DESCRIPTION

The CS18LV40965 is a high performance, high speed, and super low power CMOS Static Random Access Memory organized as 524,288 words by 8 bits and operates from a wide range of 4.5 to 5.5V supply voltage. Advanced 0.15um CMOS technology and circuit techniques provide both high speed and low power features with a typical CMOS standby current of 2.5uA and maximum access time of 55/70ns in 5.0V operation.

The CS18LV40965 has an automatic power down feature, reducing the power consumption significantly when chip is deselected. The CS18LV40965 is available in JEDEC standard 32-pin sTSOP 1 -8x13.4 mm, TSOP 1 -8x20mm, TSOP 2 -400mil, SOP -450 mil and PDIP –600mil packages.

## ■ FEATURES

Low operation voltage: 4.5 ~ 5.5V
Ultra low power consumption : 3mA@1MHz (Max.) operating current

2.5 uA (Typ.) CMOS standby current

- High speed access time : 55/70ns (Max.) at Vcc = 5.0V.
- > Automatic power down when chip is deselected.
- > Three state outputs and TTL compatible
- Data retention voltage: 2.0V(Min.)

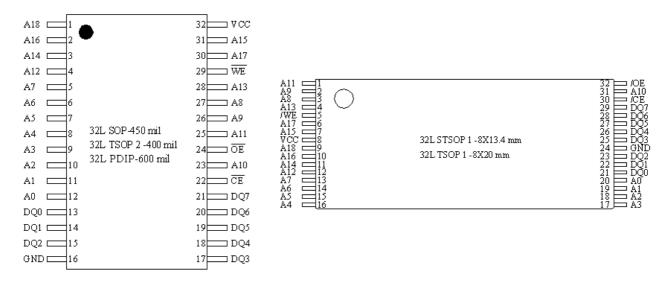
### Product Family

Product Family	Operating Temp	Standby (Typ. ) (Vcc = 5.0V)	Vcc. Range	Speed (ns)	Package Type
					32L SOP
	0~70°C	2.5 uA	4.5~5.5	55 / 70	32L STSOP 1
CS18LV40965					32L TSOP 1
C316EV40903	-40~85°C	2.5 uA			32L TSOP 2
					32L PDIP
					Dice

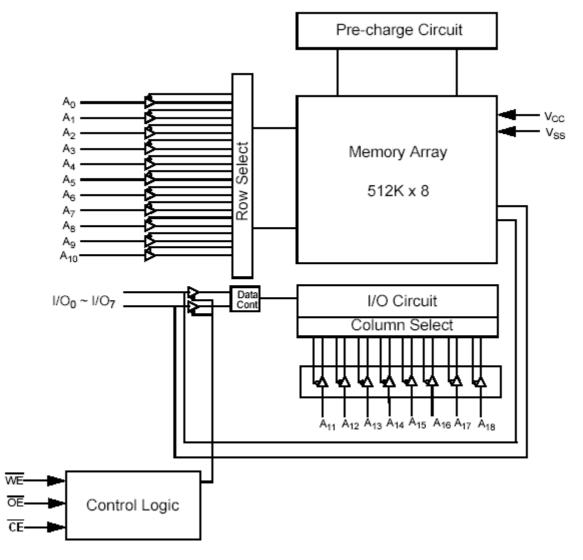


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### PIN CONFIGURATIONS



## FUNCTIONAL BLOCK DIAGRAM





# CS18LV40965

### PIN DESCRIPTIONS

Name	Туре	Function
A0 – A18	Input	Address inputs for selecting one of the 524,288 x 8 bit words in the RAM
		/CE is active LOW. Chip enables must be active when data read from or write to
/CE	Input	the device. If either chip enable is not active, the device is deselected and in a
		standby power down mode.
		The Write enable input is active LOW. It controls read and write operations. With
/WE	Input	the chip selected, when /WE is HIGH and /OE is LOW, output data will be present
	input	on the DQ pins, when /WE is LOW, the data present on the DQ pins will be written
		into the selected memory location.
		The output enable input is active LOW. If the output enable is active while the chip
/OE	Input	is selected and the write enable is inactive, data will be present on the DQ pins
		and they will be enabled.
DQ0~DQ7	I/O	These 8 bi-directional ports are used to read data from or write data into the RAM.
Vcc	Power	Power Supply
Vss	Power	Ground
NC		No connection

### TRUTH TABLE

MODE	/CE	/WE	/OE	DQ0~7	Vcc Current
Standby	Н	Х	Х	High Z	I <sub>CCSB</sub> , I <sub>CCSB1</sub>
Output Disabled	L	Н	Н	High Z	I <sub>CC</sub>
Read	L	Н	L	D <sub>OUT</sub>	I <sub>CC</sub>
Write	L	L	Х	D <sub>IN</sub>	I <sub>cc</sub>

Note: X means don't care. (Must be low or high state)

# ■ ABSOLUTE MAXIMUM RATINGS<sup>(1)</sup>

Symbol	Parameter	Rating	Unit
V <sub>IN</sub> , V <sub>OUT</sub>	Voltage on any pin relative to Vss	-0.5 to 6.0	V
V <sub>cc</sub>	V <sub>cc</sub> Voltage on Vcc supply relative to Vss		V
PD	Power Dissipation	1.0	W

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

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### OPERATING RANGE

Range	Ambient Temperature	Vcc
Commercial	0~70°C	4.5V ~ 5.5V
Industrial	-40~85°C 4.5V ~ 5.5	

1. Overshoot : Vcc +1.0V in case of pulse width  $\leq$  20ns.

2. Undershoot : - 1.0V in case of pulse width  $\leq$  20ns.

3. Overshoot and undershoot are sampled, not 100% tested.

# • CAPACITANCE <sup>(1)</sup> ( $T_A = 25^{\circ}C$ , f = 1.0 MHz)

Symbol	Parameter	Conditions		Unit
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> =0V	10	pF
C <sub>DQ</sub>	Input/Output Capacitance	V <sub>I/O</sub> =0V	10	pF

1. This parameter is guaranteed and not tested.

# **DC ELECTRICAL CHARACTERISTICS** $(T_A = 0 \text{ to } + 70^{\circ}\text{C}, \text{Vcc} = 5.0\text{V})$

Parameter Name	Parameter	Test Conduction		MIN	TYP <sup>(1)</sup>	MAX	Unit
V <sub>IL</sub>	Guaranteed Input Low Voltage <sup>(2)</sup>			-0.5		0.6	v
V <sub>IH</sub>	Guaranteed Input High Voltage <sup>(2)</sup>					Vcc+0.5	v
IIL	Input Leakage Current	$V_{CC}$ =MAX, $V_{IN}$ =0 to $V_{CC}$		-1		1	uA
l <sub>oL</sub>		ge $V_{CC}$ =MAX, /CE=V <sub>IH</sub> , or /OE=V <sub>IH</sub> , or /WE= V <sub>IL</sub> , V <sub>IO</sub> =0V to V <sub>CC</sub>		-1		1	uA
V <sub>OL</sub>	Output Low Voltage V <sub>CC</sub> =MAX, I <sub>OL</sub> = 2.1mA				0.4	v	
V <sub>OH1</sub>	Output High Voltage	V <sub>CC</sub> =MIN, I <sub>OH</sub> = -1.0mA		2.4			V
V <sub>OH2</sub>	Output High Voltage	V <sub>CC</sub> =4.5 to 5.5V, I <sub>OH</sub> = -0.1mA		V <sub>CC</sub> -0.5			V
I <sub>cc</sub>	Operating Power	/CE=V <sub>IL</sub> , I <sub>IO</sub> =0mA, F=F <sub>MAX</sub> <sup>(3)</sup> ,	55			55	mA
	Supply Current	100%duty, $V_{IN}$ = $V_{IL}$ or $V_{IH}$	70			45	
I <sub>CCSB</sub>	Standby Supply - TTL /CE=V <sub>IH</sub> , $I_{UO}$ =0mA, other pins= $V_{IL}$ or $V_{IH}$				1	mA	
I <sub>CCSB1</sub>	Standby Current -CMOS	/CE $\geq$ V <sub>CC</sub> -0.2V, V <sub>IN</sub> $\geq$ V <sub>CC</sub> -0.2V $\leq$ 0.2V	or V <sub>IN</sub>		2.5	20	uA

1. Typical characteristics are at  $T_A = 25^{\circ}C$  and not 100% tested.

2. These are absolute values with respect to device ground and all overshoots due to system or tester notice are included.

3. Fmax =  $1/t_{RC}$ .



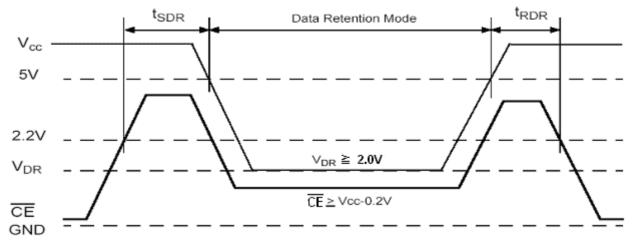
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## **DATA RETENTION CHARACTERISTICS** ( $T_A = 0$ to + 70°C)

Parameter Name	Parameter	Test Conduction	MIN	ТҮР	MAX	Unit
M		/CE $\geq$ V <sub>CC</sub> -0.2V,	2.0			V
V <sub>DR</sub>	V <sub>cc</sub> for Data Retention	$V_{IN} {\geq} V_{CC}$ -0.2V or $V_{IN} {\leq} 0.2V$	2.0			V
I <sub>CCDR</sub>		$/CE \ge V_{CC}$ -0.2V, $V_{CC}$ =2.0V		1	7	
		$V_{IN} \ge V_{CC}$ -0.2V or $V_{IN} \le 0.2V$				uA
t <sub>sDR</sub>	Chip Deselect to Data		0			20
	Retention Time	See Retention Waveform	0			ns
t <sub>RDR</sub>	Operation Recovery		t <sub>RC</sub> (1)			20
	Time		۳RC (۱)			ns

1.Read Cycle Time

## LOW Vcc DATA RETENTION WAVEFORM (/CE Controlled)



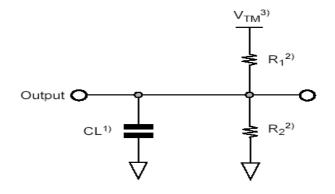
## AC TEST CONDITIONS

Input Pulse Levels: Vcc/0V

Input Rise and Fall Times: 1V/ns

Input and Output Timing Reference Level: 0.5Vcc

Output Load (See right)



Note: 1. Including scope and jig capacitance

- 2. R<sub>1</sub>=1800 ohm, R<sub>2</sub>=990 ohm
- 3.  $V_{TM} = V_{CC}$

4. L= 5pF + 1 TTL (measurement with  $t_{LZ}$ ,  $t_{OLZ}$ ,  $t_{OHZ}$ ,  $t_{WHZ}$ )



### ■ KEY TO SWITCHING WAVEFORMS

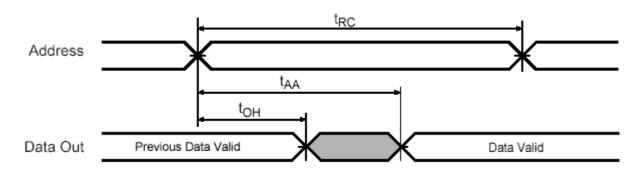
WAVEFORMS	INPUTS	OUTPUTS		
	MUST BE STEADY	MUST BE STEADY		
MAY CHANGE FROM H TO L WILL BE CHANGE FROM H TO L				
	MAY CHANGE FROM L TO H WILL BE CHANGE FROM L TO H			
	DON'T CARE ANY CHANGE PERMITTED	CHANGE STATE UNKNOWN		
DOES NOT APPLY CENTER LINE IS HIGH IMPEDANCE OF				

## ■ AC ELECTRICAL CHARACTERISTICS ( $T_A = 0$ to + 70°C, Vcc = 5.0V) [READ CYCLE]

JEDEC	Parameter	Description	5	5	7	0	Unit
Name	Name	Description	MIN	MAX	MIN	MAX	Unit
t <sub>avax</sub>	t <sub>RC</sub>	Read Cycle Time	55		70		ns
t <sub>AVQV</sub>	t <sub>AA</sub>	Address Access Time		55		70	ns
t <sub>ELQV</sub>	t <sub>co</sub>	Chip Select Access Time (/CE)		55		70	ns
t <sub>GLQV</sub>	t <sub>oe</sub>	Output Enable to Output Valid		30		35	ns
t <sub>ELQX</sub>	t <sub>LZ</sub>	Chip Select to Output Low Z (/CE)	10		10		ns
t <sub>GLQX</sub>	t <sub>oLZ</sub>	Output Enable to Output in Low Z	5		5		ns
t <sub>EHQZ</sub>	t <sub>HZ</sub>	Chip Deselect to Output in High Z (/CE)	0	20	0	25	ns
t <sub>GHQZ</sub>	t <sub>oнz</sub>	Output Disable to Output in High Z	0	20	0	25	ns
t <sub>AXOX</sub>	t <sub>он</sub>	Out Disable to Address Change	10		10		ns

## SWITCHING WAVEFORMS

#### **READ CYCLE (1) (Address Transition Controlled)**

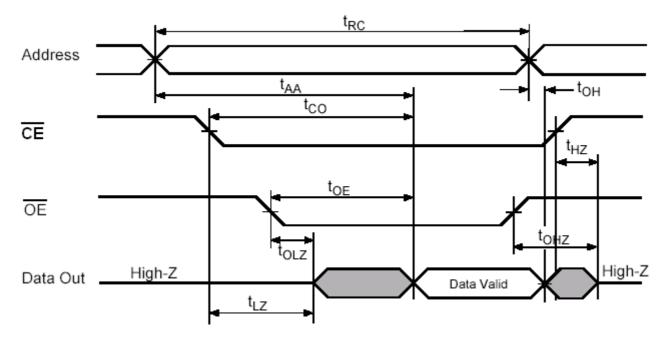


Chiplus reserves the right to change product or specification without notice.



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#### **READ CYCLE (2) (/OE Controlled)**



#### NOTES:

- 1. t<sub>HZ</sub> and t<sub>OHZ</sub> are defined as the outputs achieve the open circuit conditions and are not referenced to output voltage levels.
- 2. At any given temperature and voltage condition,  $t_{HZ}(Max.)$  is less than  $t_{LZ}(Min.)$  both for a given device and from device to device interconnection.

## ■ AC ELECTRICAL CHARACTERISTICS ( $T_A = 0$ to + 70°C, Vcc = 5.0V) [WRITE CYCLE]

JEDEC	Parameter	Description	5	55		70	
Name	Name		MIN	MAX	MIN	MAX	
t <sub>avax</sub>	t <sub>wc</sub>	Write Cycle Time	55		70		ns
t <sub>∈1LWH</sub>	t <sub>cw</sub>	Chip Select to End of Write	45		60		ns
t <sub>avwl</sub>	t <sub>AS</sub>	Address Setup Time	0		0		ns
t <sub>avwh</sub>	t <sub>AW</sub>	Address Valid to End of Write	45		60		ns
t <sub>wLWH</sub>	t <sub>wP</sub>	Write Pulse Width	40		50		ns
t <sub>whax</sub>	t <sub>wR</sub>	Write Recovery Time (/CE, /WE)	0		0		ns
t <sub>wLQZ</sub>	t <sub>wHZ</sub>	Write to Output in High Z	0	20	0	20	ns
t <sub>DVWH</sub>	t <sub>DW</sub>	Data to Write Time Overlap	25		30		ns
t <sub>whdx</sub>	t <sub>DH</sub>	Data Hold from Write Time	0		0		ns
t <sub>whox</sub>	t <sub>ow</sub>	End of Write to Output Active	5		5		ns

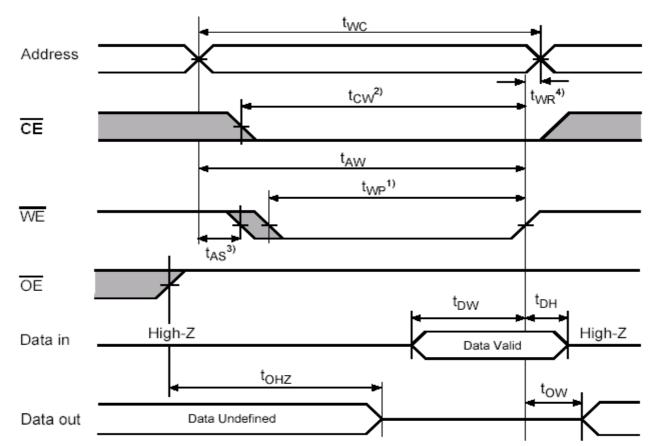
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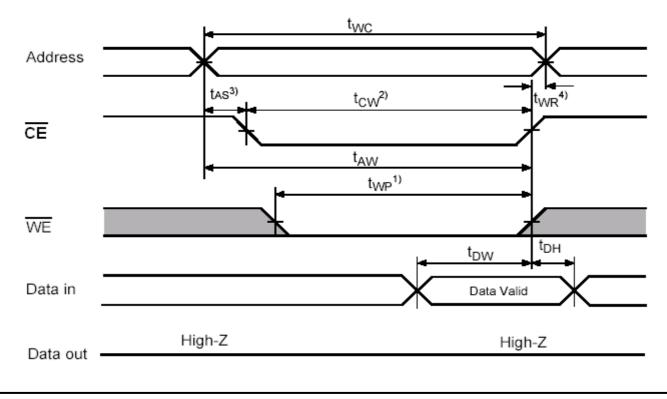
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### SWITCHING WAVEFORMS

WRITE CYCLE (1) (/WE Controlled, /OE High During WRITE)



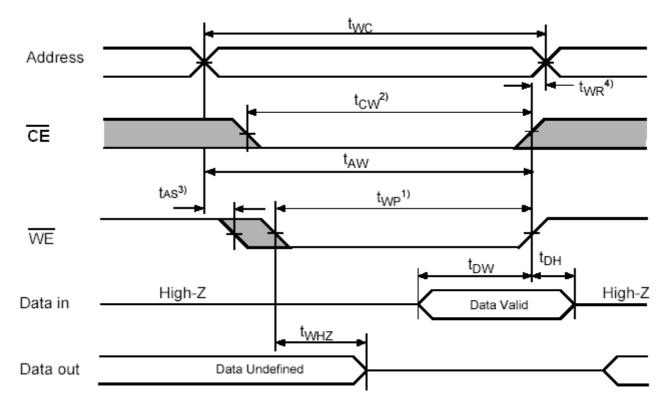
#### WRITE CYCLE (2) (/CE Controlled)





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#### WRITE CYCLE (3) (/WE Controlled, /OE LOW)

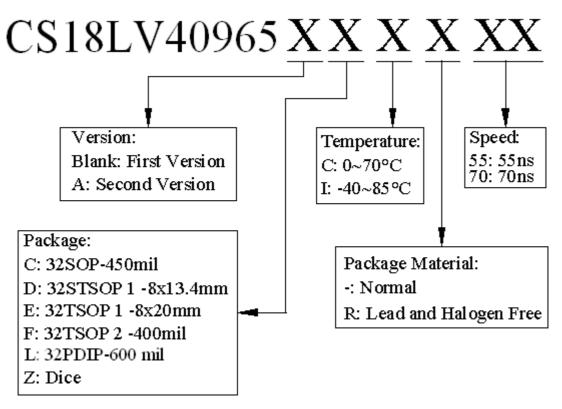


#### NOTES:

- A write occurs during the overlap(t<sub>WP</sub>) of low /CE and low /WE. A write begins at the latest transition among /CE goes low and /WE goes low. A write ends at the earliest transition when /CE goes high and /WE goes high. The t<sub>WP</sub> is measured from the beginning of write to the end of write.
- 2.  $t_{CW}$  is measured from the /CE going low to end of write.
- 3.  $t_{AS}$  is measured from the address valid to the beginning of write.
- 4. t<sub>WR</sub> is measured from the end of write to the address change. t<sub>WR</sub> applied in case a write ends as /CE or /WE going high.



### ORDER INFORMATION

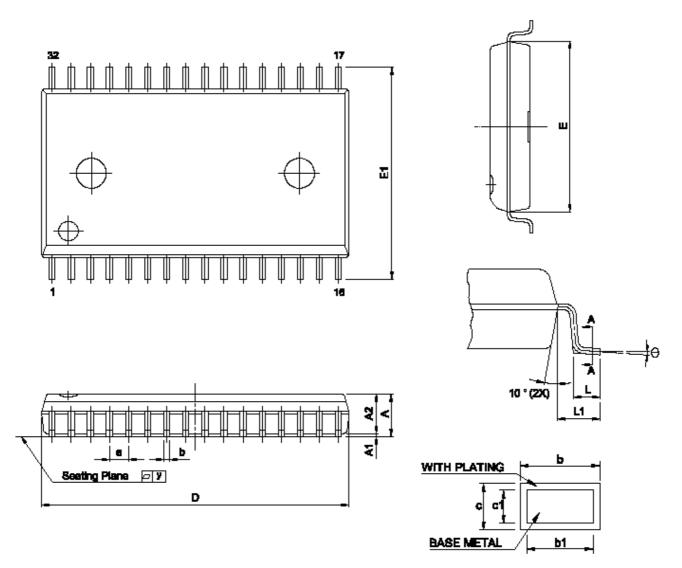


Note: Package material code "R" meets ROHS



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## PACKAGE DIMENSIONS - 32L SOP 450 mll



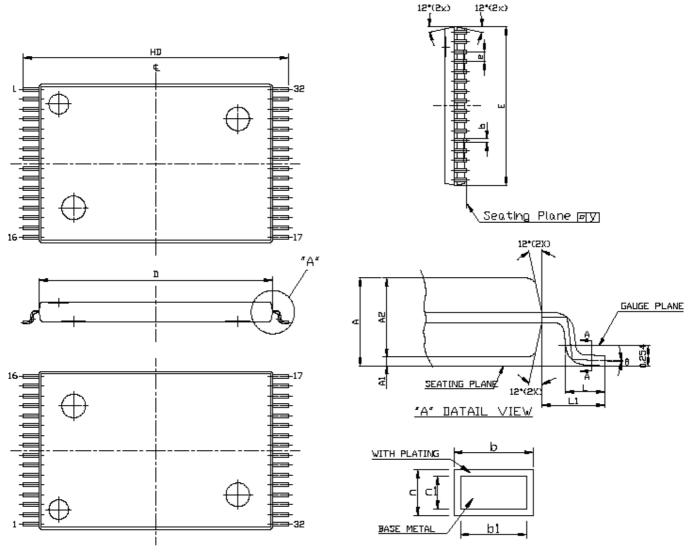
SECTION A-A

8Y	MBOL	A	A1	A2	Ь	ы	C	c1	D	E	E1	8	L	L1	у	Θ
	Min.	2.645	0.102	2.540	0.35	0.35	0.15	0.15	20.320	11.178	13.792	1.118	0.584	1.194	-	0"
mm	Nom.	2.821	0.229	2.680	-	-	-	-	20.447	11.303	14.097	1.270	0.834	1.397	-	-
	Mex.	2.997	0.358	2.820	0.50	0.48	0.32	0.28	20.574	11.430	14.402	1.422	1.084	1.600	0.1	10*
	Min.	0.104	0.004	0.1000	0.014	0.014	0.006	0.008	0.800	0.440	0.543	0.044	0.023	0.047	-	Q"
Inch	Nom.	0.111	0.009	0.1055	_	_	_	-	0.805	0.445	0.555	0.050	0.033	0.055	-	_
	Max.	0.118	0.014	0.1110	0.020	0.018	0.012	0.011	0.810	0.450	0.687	0.058	0.043	0.063	0.004	10"



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## PACKAGE DIMENSIONS: 32L STSOP 1-8x13.4mm



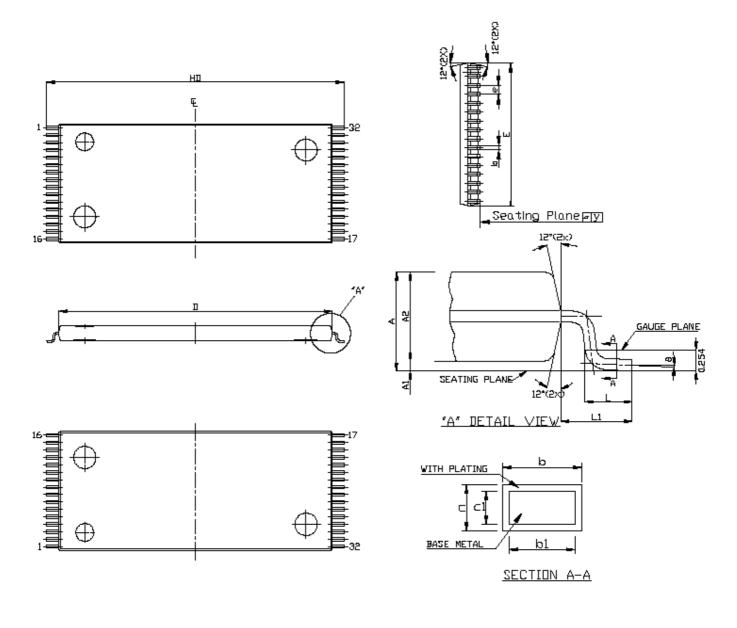
SECTION A-A

	MBOL	A	A1	5A	b	b1	с	c1	D	E	е	HD	L	L1	у	Θ
	Min.	1.00	0.05	0.95	0.17	0.17	0.10	0.10	11.70	7.90	0.40	13.20	0.40	0.70	-	0°
mm	Nom.	1.10	0.10	1.DO	0.22	0.20	-	-	11.80	B.OD	D.5D	13.40	D.5D	D.80	-	-
	Max.	1.2D	0.15	1.05	0.27	0.23	0.21	0.16	11.90	8.10	D.6D	13.60	D.7D	D.9D	D.1	8°
	Min.	D.0393	0.002	0.037	0.007	0.007	0.004	0.004	0.461	0.311	D.016	0.520	0.D157	0.0275	-	0"
inch	Nom.	0.0433	0.004	0.039	0.009	0.008	-	_	0.465	0.315	0.020	D.528	0.D197	0.0315	-	-
	Max.	D.0473	0.006	0.041	0.011	0.009	0.008	0.006	0.469	0.319	0.024	D.536	0.0277	0.0355	0.0D4	8°



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## PACKAGE DIMENSIONS: 32L TSOP 1-8x20mm

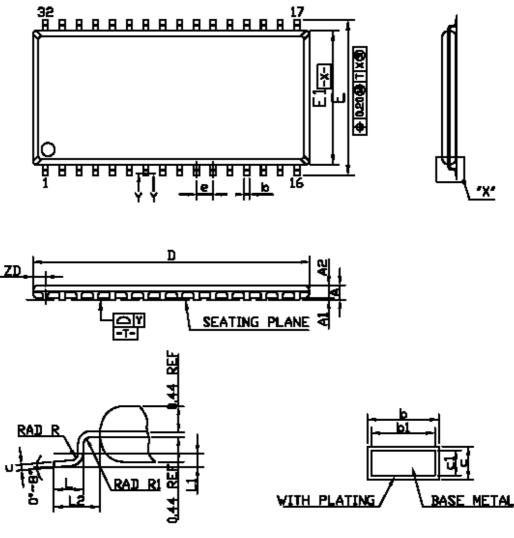


UNIT	MBOL	A	A1	A2	b	b1	с	с1	D	E	e	HD	L	L1	У	Θ
	Min.	1.00	0.D5	0.95	0.17	0.17	0.10	0.10	1B.30	7.90	D.40	19.80	D.4D	D.7D	-	0*
mm	Nom.	1.10	0,10	1.00	0.22	0,20	-	-	1B,40	8.00	D.50	20.00	0.50	0.80	-	-
	Max.	1,20	0.15	1.05	0,27	0,23	0,21	0,16	18,50	8,10	0.60	20,20	0,70	0,90	0.1	8°
	Min.	D.0393	0.002	0.037	0.007	0.007	0.004	0.004	0.720	0.311	0.016	0.779	0.0157	0.0275	-	0°
inch	Nom.	0.0433	0.004	0.039	0.009	0.008	-	-	0.724	0.315	0.020	0.787	0.0197	0.0315	-	-
	Max.	0.0473	0.006	0.041	0.011	0.009	0.008	0.006	0.728	0.319	0.024	0.795	0.0277	0.0355	0.004	8°



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## PACKAGE DIMENSIONS: 32L TSOP 2-400mll



DETAIL "X"

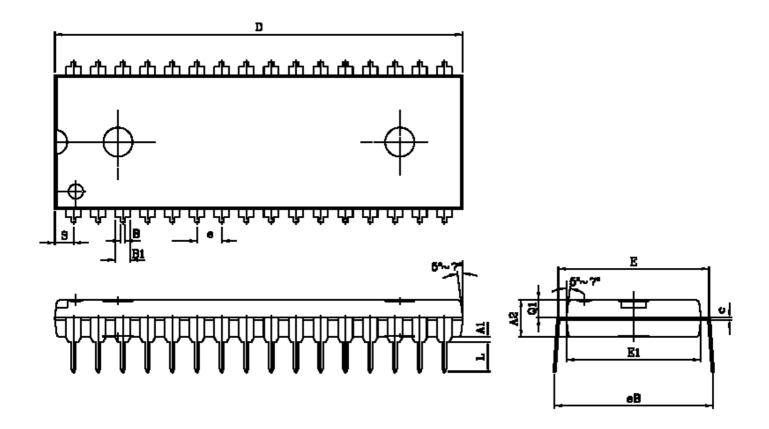
SECTION Y-Y

		A	A1	A2	b	<b>b</b> 1	с	<b>c</b> 1	D	E	E1	e	L	L1	٢s	R	<b>R</b> 1	ZD	Y
	Min.	1	0.05	0.95	0.30	0.30	0.12	0.10	20.82	11.56	10.03		0.40	0.25 bsc	0.8 ref	0.12	0.12	0.95 ref	-
mm	Nom.	1	0.10	1.00	-	0.40	-	0.127	20.95	11.76	10.16	DSC	0.50			-	-		-
	Max.	1.20	0.15	1.05	0.52	0.45	0.21	0.16	21.08	11.96	10.29		0.60			0.25	-		0.10
	Min.	I	0.002	0.037	0.012	0.012							0.016			0.005		0.037 _ ref	-
Inch	Nom.	-	0.004	0.039	-	0.016	-	0.005	0.823	0.463	0.400	0.050 bsc	0.020	0.010 0 bsc	0.031 ref	1	-		-
	Max.	0.047	0.006	0.042	0.020	0.019	0.008	0.006	0.830	0.471	0.405		0.024		1.51	0.010	-		0.0 <b>04</b>



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PACKAGE DIMENSIONS - 32L PDIP -600mil



		<b>A</b> 1	A2	в	B1	c	D	E	E1	8	<b>eB</b>	L	s	Q1
	Min.	0.254	3.785	0.330	1.143	0.152	41.783	1 <b>4.986</b>	13.716		16.002	3.048	1.651	1.651
mm	Nom.	-	3.912	0.457	1.270	0.254	41.910	15.240	13.818	(119)	16.510	3.302	1.905	1.778
	Max.	-	4.039	0.584	1.397	0.356	42.037	15. <b>49</b> 4	13.920		17.018	3.556	2 <b>.159</b>	1.905
	Min.	0.010	0.149	0.013	0.045	0.006	1.645	0.590	0.540		0.630	0.120	0.065	0.065
inch	Nom.	-	0.154	0.018	0.050	0.010	1.850	0.600	0.544	0.100 (TYP)	0.850	0.130	0.075	0.070
	Max.	-	0.159	0.023	0.055	0.014	1.655	0.610	0.548	<b>, ,</b>	0.670	0.140	0.085	0.075